Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/714,310	CHEN ET AL.		
Examiner	Art Unit		
Terra C. Gibbs	1635		

SEARCHED					
SEARCHED					
Class	Subclass	Date	Examiner		
536	24.1 24.3 24.33 24.5	6/24/2006	TCG		

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Inventor name search in PALM	6/24/2006	TCG
STIO score/length search of SEQ ID NO:21 with cutoff parameters at 75% Note: SEQ ID NO:17 is comprised within SEQ ID NO:21	6/24/2006	TCG
Also note that SEQ ID NO:32 is the complement of SEQ ID NO:17, plus an additional nucleotide	6/24/2006	tcg
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